DOCKET NO.: 4940

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN THE MATTER OF THE APPLICATION FOR PATENT

OF: Hitoshi SUMIYA et al.

SERIAL NO.: to be assigned - new

FILED: March 17, 2006

FOR: DIAMOND TOOL, SYNTHETIC SINGLE CRYSTAL DIAMOND AND METHOD OF SYNTHESIZING SINGLE CRYSTAL DIAMOND, AND DIAMOND JEWELRY

PCT International Application: PCT/JP2004/014910 PCT International Filing Date: October 8, 2004

COMMISSIONER FOR PATENTS P.O. BOX 1450 ALEXANDRIA, VA 22313-1450

March 17, 2006

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98 applicants enclose a Form PTO-1449, copies of references AH to AJ, AL, AN to AS and AX cited thereon, English Abstracts as indicated on Form PTO-1449, and a copy of the International Search Report issued on January 18, 2005 in the corresponding PCT International Application. Copies of references AF, AG, AK, AM and AT to AW are not (and need not be) enclosed, because they have been transmitted to the USPTO by the International Searching Authority in the International processing of this PCT application.

USPS EXPRESS MAIL ED 636 851 893 US MAR 17 2006

- 2) This Information Disclosure Statement is being filed simultaneously with the above identified new patent application.
- References AA to AG and AX are in English. Reference AH corresponds to AA, AJ corresponds to AB, AL corresponds to AC, AM+AN+AO correspond to AE, and AT corresponds to AD, from which the relevance can be determined in English. References AH to AW are accompanied by English Abstracts. References AH, AJ, AL, AN to AT and AX have been discussed at pages 2 to 4 and 6 of the present specification. Therefore no further discussion of the references is necessary.
- Moreover, the enclosed Search Report indicates the degree of relevance of references AF, AG, AK, AM and AT to AW by category ("X" means relevant to anticipation or obviousness when considered alone; "Y" means relevant to obviousness when combined with another reference; and "A" means technological background). Thereby a concise explanation of the relevance has been provided (see MPEP §609).
- The Examiner is requested to consider all references of record, return an initialed copy of the enclosed Form PTO-1449 and ensure that all references of record are printed on any patent issuing from this application.

MP20RC36FCINIO 17 MAR 2006

6) Favorable consideration and allowance of claims 1 to 36 are respectfully requested.

> Respectfully submitted, <u>Hitoshi SUMIYA et al. - Applicant</u>

WFF:ks/4940 Enclosures: postcard, Form PTO-1449, 11 references, 16 English abstracts, copy of Intern. Search Report

Walter F. Fasse Patent Attorney Reg. No.: 36132

Tel. No.: 207-862-4671 Fax. No.: 207-862-4681 P.O. Box 726

Hampden, ME 04444-0726

14P20 RED'G POTITTO 17 MAR 2006

Sheet <u>1</u> of <u>2</u> IDS LIST OF REFERENCES CITED BY APPLICANT (FORM PTO-1449) DATED: March 17, 2006

Atty. Docket No.: 4940

16 serial No: 3 6

Applicant: Hitoshi SUMIYA et al.

U.S. Filing Date: March 17, 2006 Art Unit: 3723

U. S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	с1.	Sub- Cl.	Fil. Date
/DVN/	AA	4,617,181	10/1986	Yazu et al.	-	_	-
9999999	AB	5,078,551	01/1992	Oomen	-	_	-
0000000	AC	5,133,332	07/1992	Tanaka et al.	-	_	-
/DVN/	AD	6,030,595	02/2000	Sumiya et al.		_	-
/DVN/	AE	6,129,900	10/2000	Satoh et al.	_	-	_

FOREIGN PATENT DOCUMENTS

			DOCUMENT NO.	DATE	COUNTRY	Cl.	Sub- Cl.	English	
,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,		nagga garannan		04/1995	201008	00000000000	000000000000000000000000000000000000000		
000000000000000000000000000000000000000			QQQQ	02/1999					
· /DVN/ ,		АН	60-012747	01/1985	Japan	_	<u>-</u>	Abstract,	
		AI	02-198704	08/1990	Japan	_	-	Abstract	
		AJ	03-131407	06/1991	Japan	-	-	Abstract, = AB	
		AK	03-217226	09/1991	Japan	-	-	Abstract	
V	,	AL	03-228504	10/1991	Japan	-	-	Abstract, = AC	
/DVN/	1 .	АМ	05-058786	03/1993	Japan	-	-	Abstract, = AE	

OTHER DOCUMENTS

EXAMINER'S SIGNATURE

DATE CONSIDERED

/Dung Van Nguyen/

11/07/2007

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

USPS EXPRESS MAIL ED 636 851 893 US MAR 17 2006

MP20R332T07770 17 MAR 2006

Atty. Docket No.: Serial No. Sheet 2 of 2 IDS LIST OF REFERENCES CITED 4940 to be assigned BY APPLICANT Applicant: Hitoshi SUMIYA et al. (FORM PTO-1449) DATED: March 17, 2006 Art Unit: U.S. Filing Date: March 17, 2006 3723 U. S. PATENT DOCUMENTS *EXAMINER DOCUMENT NO. DATE NAME Cl. Sub-Fil. INITIAL Cl. Date FOREIGN PATENT DOCUMENTS Sub-Cl. DOCUMENT NO. DATE COUNTRY English Cl. 06/1993 /DVN/ AN 05-137999 Japan Abstract, = AE 06/1993 05-138000 ΑO Japan Abstract, = AE 08/1993 AP 05-200271 Japan Abstract 05-329356 12/1993 ΑQ Japan Abstract 07/1994 06-182182 AR Japan Abstract 07/1994 06-182184 AS Japan Abstract AΤ 07-116494 05/1995 Japan Abstract, = AD04/1999 AU 11-100297 Japan Abstract ΑV 11-300194 11/1999 Japan Abstract /DVN/ 05/2003 AW 2003-137686 Japan Abstract OTHER DOCUMENTS ΑX H. Sumiya, S. Satoh, "High-Pressure Synthesis of High-Purity Diamond /DVN/ Crystal", Diamond and Related Materials 5 Elsevier Science S.A., 1996 pp. 1359-1365 EXAMINER'S SIGNATURE DATE CONSIDERED /Dung Van Nguyen/ 11/07/2007

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

USPS EXPRESS MAIL ED. 636 851 893 US MAR 17 2006